IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Ín re application of:

Yeong-Kwang Kim et al.

Serial No.

09/872,203

Examiner:

Julio J. Maldonado

Confirmation No.: 1930

Filed:

May 31, 2001

Group Art Unit:

2823

For:

METHOD OF FORMING A THING FILM USING ATOMIC LAYER DEPOSITION

Assistant Commissioner for Patents, Washington, D.C. 20231

Responsive to the Office Action dated October 4, 2002, enclosed is an amendment in the above-identified application.

The fee has been calculated as shown below.

	CLAIM	IS AS AMEN	NDED		
For:	Number After Amendment	Previous Number	Extra	Rate	Additional Fee
Total Claims	42	41	1	x \$18 =	\$18.00
Independent Claims	5	5	0	x \$84 =	\$0
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT		1			\$18.00

^{*}greater of twenty (20) or number for which fee has been paid

PTO Form 2038 authorizing credit card payment for the above-listed fees is enclosed. \boxtimes

Any deficiency or overpayment should be charged or credited to deposit account number 13-1703.

Respectfully submitted,

MARGER JOHNSON & McCOLLOM, P.C.

20575 PATENT TRADEMARK OFFICE

Reg. No. 39,286

MARGER JOHNSON & McCOLLOM, P.C. 1030 SW Morrison Street Portland, OR 97205 (503) 222-3613

HEREBY CERTIFY THAT THIS COR-RESPONDENCE IS BEING DEPOSITED WITH THE UNITED STATES POSTAL SEAVICE AS FIRST CLASS MAIL IN AN ENVELOPE ADDRESSED TO:

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PATENT APPLICATION Do. No. 2522-1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Yeong-Kwang KIM, et al.

Serial No.

09/872,203

Examiner:

Maldonado, Julio J

Confirmation No. 1930

Filed:

May 31, 2001

Group Art Unit: 2823

For:

METHOD OF FORMING A THING FILM USING ATOMIC LAYER

DEPOSITION

Assistant Commissioner for Patents Washington, D.C. 20231

RESPONSE TO OFFICE ACTION

Responsive to the Office Action, dated October 4, 2002, please amend the application as follows.

IN THE SPECIFICAITON

Pleaser change the paragraph at page 7, line 26, to page 8, line 2, with the following:

These steps allow the non-chemically adsorbed portion of the first reactants 40 in the reactor 10 to be diluted in a very short period of time, for example, a few seconds, thus drastically reducing the overall purging time and purging efficiency during a purging step 32 compared to conventional ALD techniques. This dilution process significantly reduces the partial pressure of the non-chemically adsorbed portion of the first reactants 40 in the ALD reactor 10. Thus, only a very small amount of the non-chemically adsorbed portion of the first reactants 40 remain in the reactor 10 after the removal of the non-chemically adsorbed portion of the first reactants 40 as the reactant 40 is already diluted, thus maximizing purging efficiency. Also, because the first reactants 40 are diluted, intermixing between the first reactants 40 can be sufficiently prevented.

IN THE CLAIMS

1. A method of forming a thin film using atomic layer deposition (ALD), comprising:

Docket No. 2522-11

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